

### IN THE UNITED STATES PATENT AND TRADEMARK OFFICE



'În re Application

SC/Serial No.: SEE SCHEDULE A

Filed: Title:

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Customer No. 239

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Tina M. Galdos

(Signature)

Signature Date: December 17, 2002

**CHANGE OF ADDRESS** 

Commissioner for Patents Washington, DC 20231

Sir:

I am the attorney of record for the patents and patent applications listed on Schedule A attached hereto. Please be notified that my address has changed to the following:

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Please send all future correspondence concerning the patent and patent applications listed on

Schedule A to the above address.

Respectfu

12-17-02

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## LIST OF ISSUED PATENTS

l	Title	Filing Date	U.S. Serial No.	Issue Date	Patent No.	Old (BDSM) Attorney	<u> </u>
	Null Test Fourier Domain Alignment Technique for Phase-Shifting Point Diffraction Interferometer	1/12/1999	09/229,449	8/29/2000		6,111,646	6,111,646 015780-024
	Phase-Shifting Point Diffration Interferometer Mask Designs	10/21/1998	09/176,617	10/23/2001		6,307,635	6,307,635 015780-025
L	Phase-Shifting Point Diffraction Interferometer Grating Designs	10/21/1998	09/176,695	2/27/2001		6,195,169	6,195,169 015780-027
	Phas-Shifting Point Diffraction Interferometer Focus-Aid Enhanced Mask	7/26/1999	09/361,780	11/21/2000		6,151,115	6,151,115 015780-028
<u> </u>	Dual-Domain Point Diffraction Interferometer	4/27/1999	09/300,539	8/8/2000		6,100,978	6,100,978 015780-030
<u></u> _	In Situ Alignment System for Phase Shifting Point-diffraction Interferometry	6/2/1999	09/324,903	9/12/2000		6,118,535	6,118,535 015780-031
	Phase-Shifting Point Diffraction Interferometer Phase Grating Designs	10/14/1999	09/419,703	7/24/2001		6,266,147	6,266,147 015780-032
	Interferometric At-Wavelength Flare Characterization of EUV Optical System	7/28/2000	09/627,533	5/15/2001		6,233,056	6,233,056 015780-033
	Method of Fabricating Reflection-Mode EUV- Diffraction Elements	12/5/2000	09/730,970	5/21/2002		6,392,792	6,392,792 015780-039

EDULE A
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### SCHEDULE A

# LIST OF PENDING PATENT APPLICATIONS

Title	Filing Date	U.S. Serial No.	Old (BDSM) Attorney Docket No.	New (FDML) Attorney Docket No.
Method and Apparatus for Inspecting Reflection Masks for Defects	11/17/1998	09/193,198	015780-026	LBLL-01026US0
System for Interferometric Distortion Measuremens That Define an Optical Path	5/11/2000	09/569,168	015780-029	LBLL-01029US0
Dual-Domain Lateral Shearing Interferometer	8/4/2000	09/632,631	015780-034	LBLL-01034US0
Hybrid Shearing and Phase-Shifting Point Diffraction Interferometer	7/17/2000	09/617,719	015780-035	LBLL-01035US0
Method of Fabricating Reflection-Mode EUV Diffusers	4/30/2001	09/846,150	015780-040	LBLL-01040US0
Apparatus for Generating Partially Coherent Radiation	8/30/2001	09/944,391	015780-041	LBLL-01041US0
A Holographic Illuminator for Synchrotron-Based Projection Lithography Systems	10/16/2001	09/981,500	015780-042	LBLL-01042US0
Synchrotron-Based EUV Lithography Illuminator Simulator	6/5/2002	10/163,479	015780-043	LBLL-01043US0
Diffractive Optical Element for Extreme Ultraviolet Wavefront Control	9/17/2001	09/956,160	015780-044	LBLL-01044US0